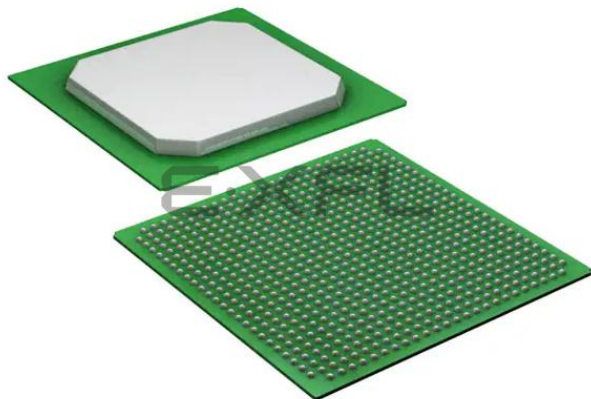




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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

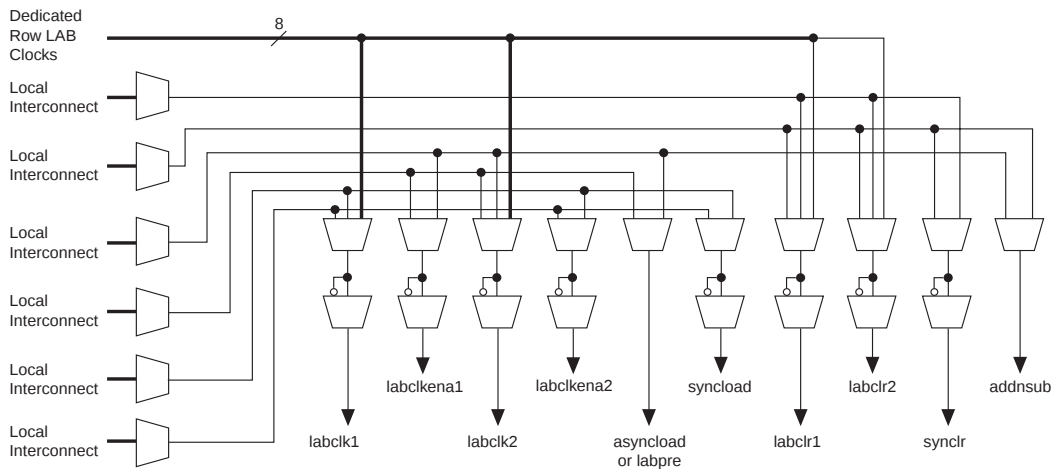
Details

Product Status	Obsolete
Number of LABs/CLBs	1846
Number of Logic Elements/Cells	18460
Total RAM Bits	1669248
Number of I/O	426
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	672-BBGA
Supplier Device Package	672-BGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep1s20b672c7

With the LAB-wide addnsub control signal, a single LE can implement a one-bit adder and subtractor. This saves LE resources and improves performance for logic functions such as DSP correlators and signed multipliers that alternate between addition and subtraction depending on data.

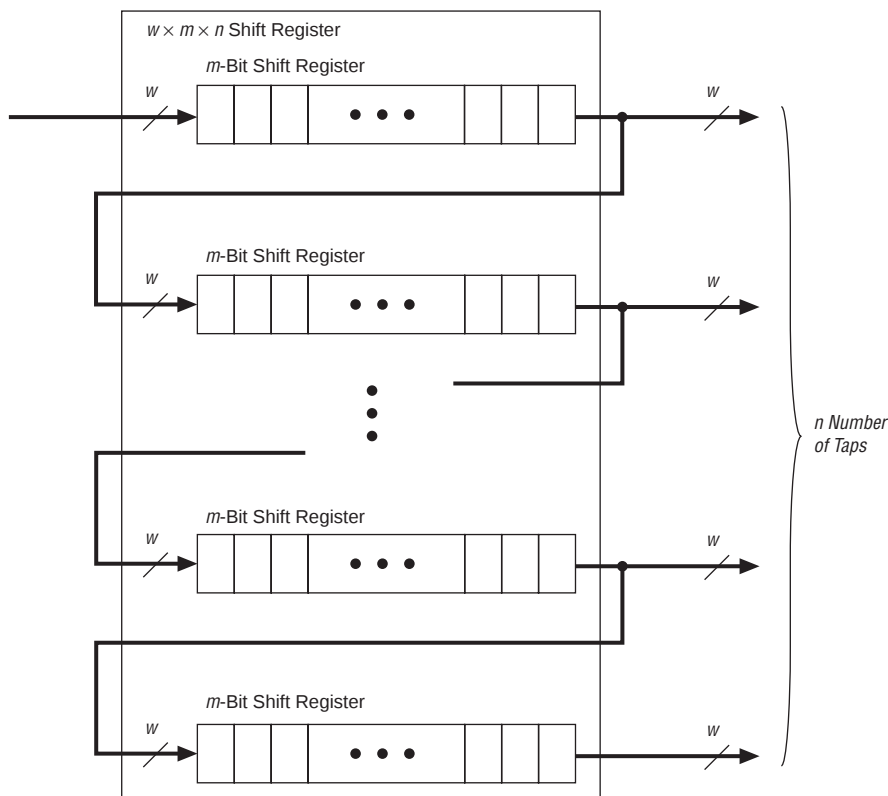
The LAB row clocks [7..0] and LAB local interconnect generate the LAB-wide control signals. The MultiTrack™ interconnect's inherent low skew allows clock and control signal distribution in addition to data. [Figure 2-4](#) shows the LAB control signal generation circuit.

Figure 2-4. LAB-Wide Control Signals



Logic Elements

The smallest unit of logic in the Stratix architecture, the LE, is compact and provides advanced features with efficient logic utilization. Each LE contains a four-input LUT, which is a function generator that can implement any function of four variables. In addition, each LE contains a programmable register and carry chain with carry select capability. A single LE also supports dynamic single bit addition or subtraction mode selectable by an LAB-wide control signal. Each LE drives all types of interconnects: local, row, column, LUT chain, register chain, and direct link interconnects. See [Figure 2-5](#).

Figure 2–14. Shift Register Memory Configuration

Memory Block Size

TriMatrix memory provides three different memory sizes for efficient application support. The large number of M512 blocks are ideal for designs with many shallow first-in first-out (FIFO) buffers. M4K blocks provide additional resources for channelized functions that do not require large amounts of storage. The M-RAM blocks provide a large single block of RAM ideal for data packet storage. The different-sized blocks allow Stratix devices to efficiently support variable-sized memory in designs.

The Quartus II software automatically partitions the user-defined memory into the embedded memory blocks using the most efficient size combinations. You can also manually assign the memory to a specific block size or a mixture of block sizes.

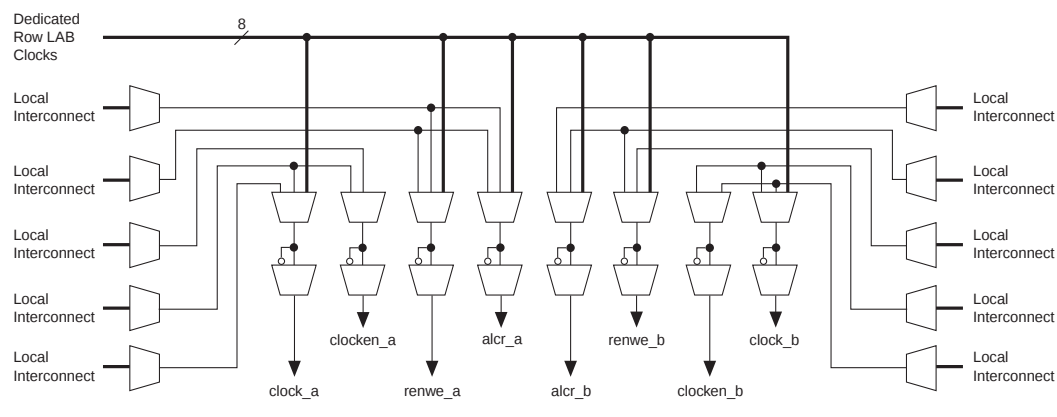
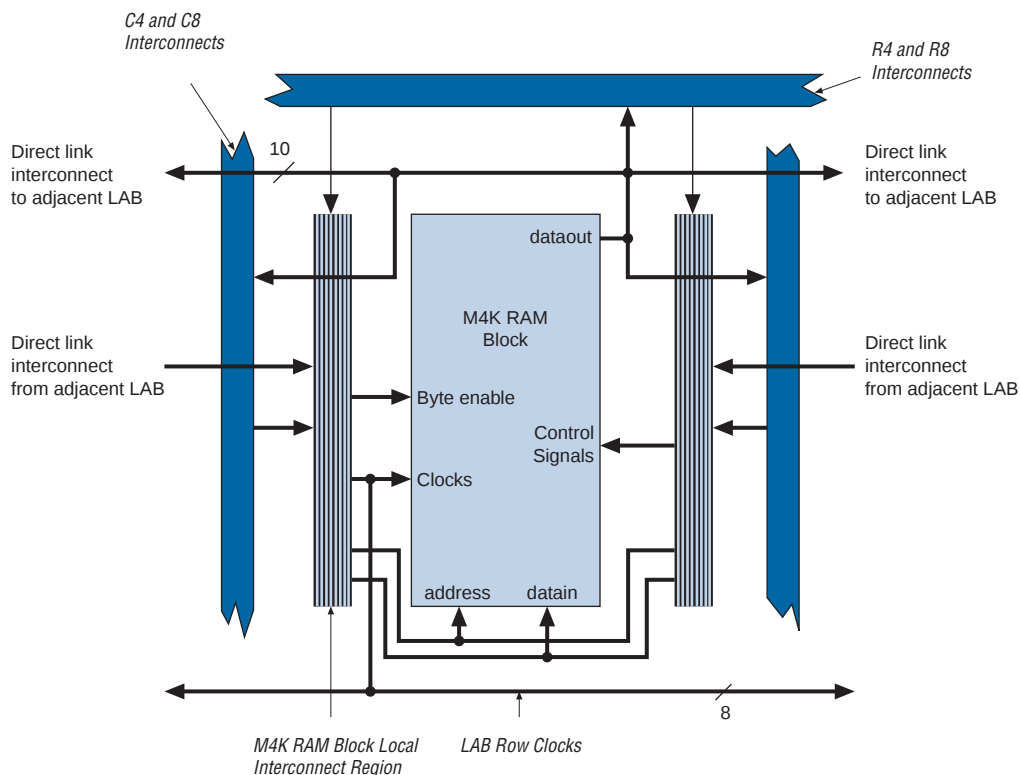
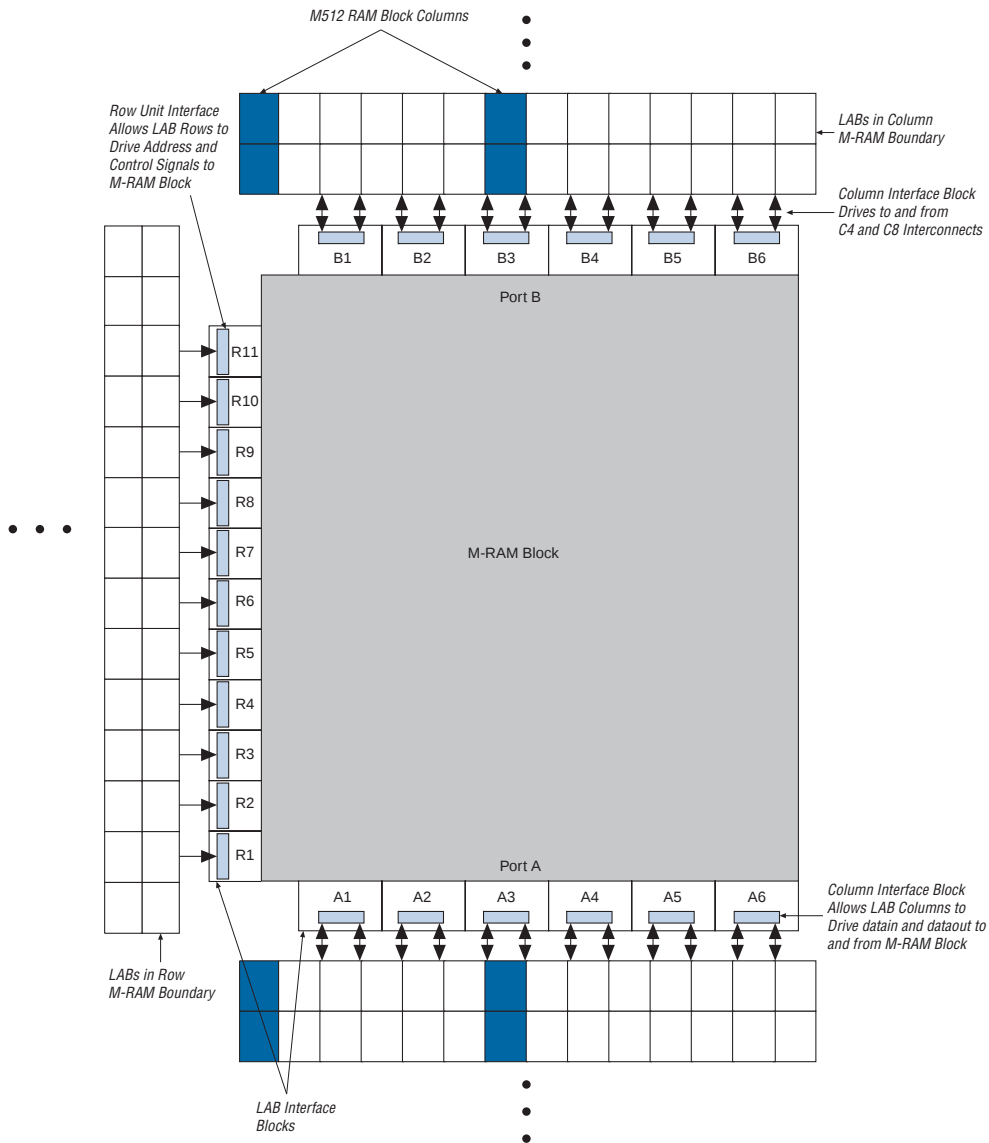
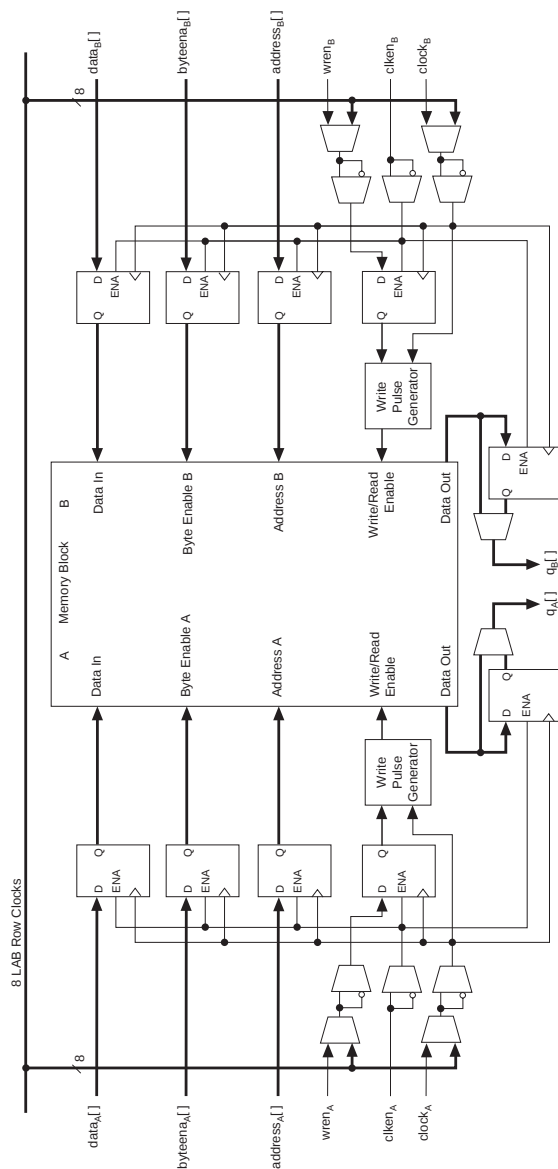
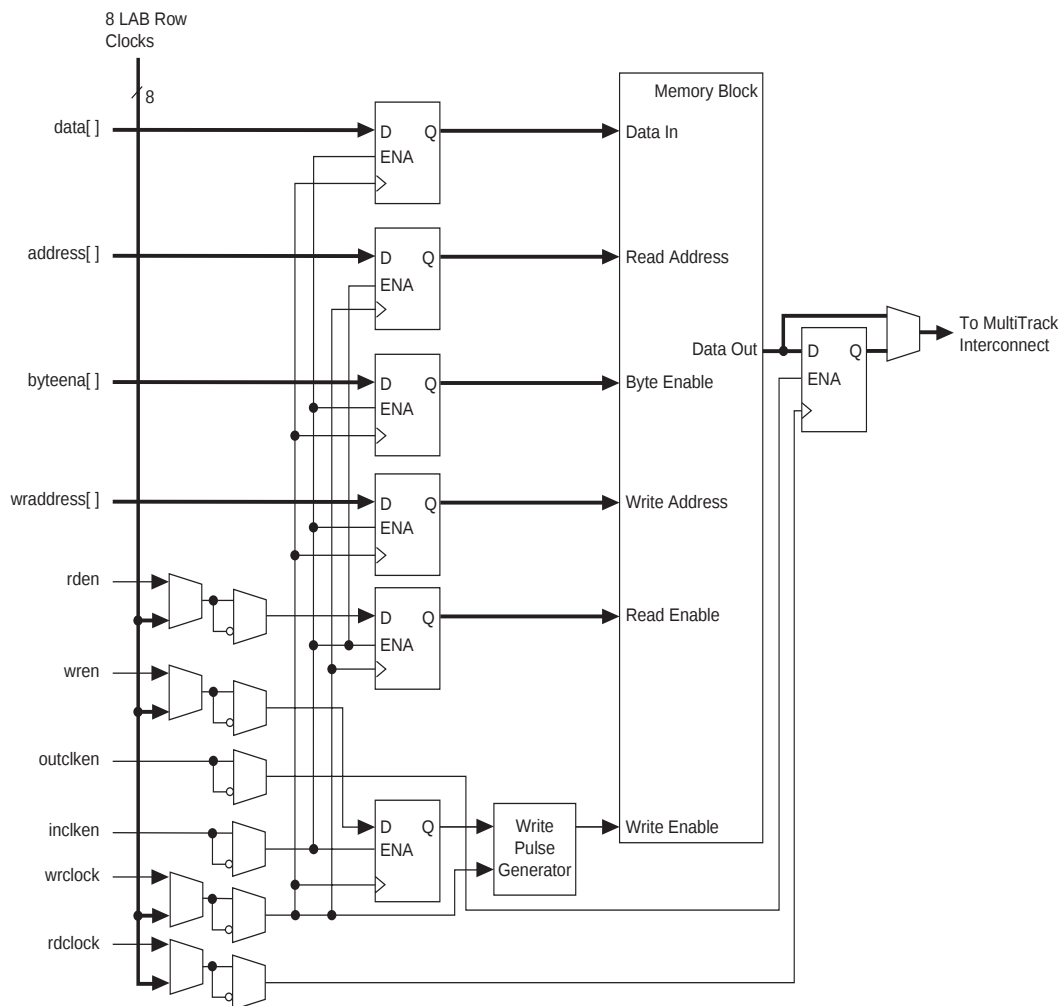
Figure 2–17. M4K RAM Block Control Signals**Figure 2–18. M4K RAM Block LAB Row Interface**

Figure 2–21. Left-Facing M-RAM to Interconnect Interface *Notes (1), (2)***Notes to Figure 2–21:**

- (1) Only R24 and C16 interconnects cross the M-RAM block boundaries.
- (2) The right-facing M-RAM block has interface blocks on the right side, but none on the left. B1 to B6 and A1 to A6 orientation is clipped across the vertical axis for right-facing M-RAM blocks.

Figure 2–24. Independent Clock Mode Notes (1), (2)**Notes to Figure 2–24**

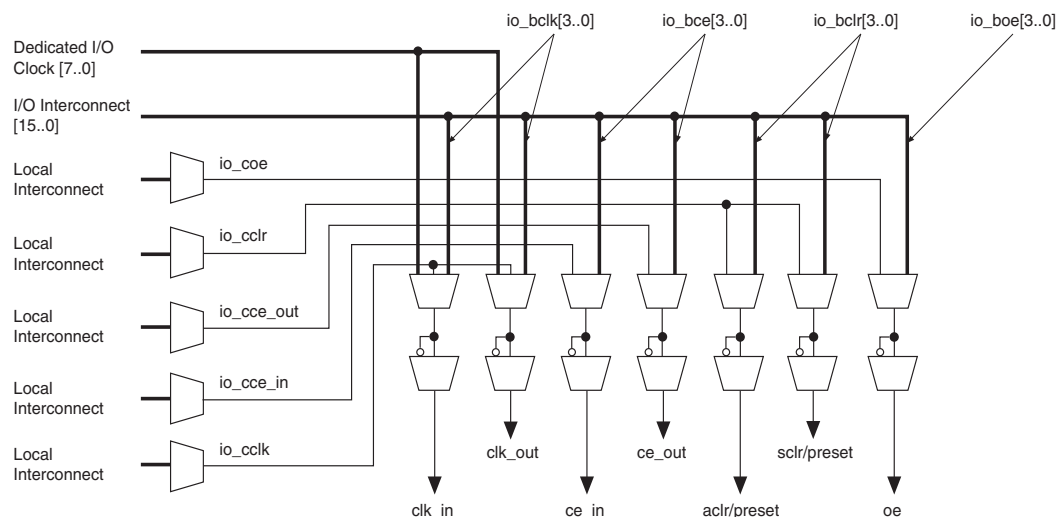
- (1) All registers shown have asynchronous clear ports.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

Figure 2–26. Input/Output Clock Mode in Simple Dual-Port Mode *Notes (1), (2)***Notes to Figure 2–26:**

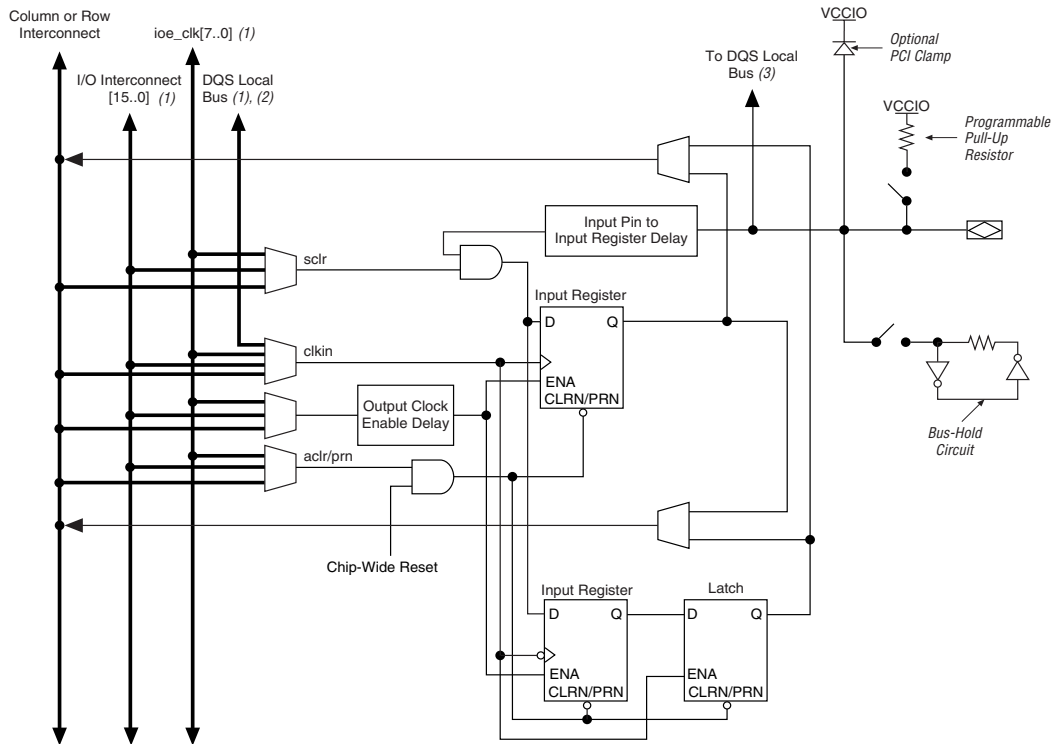
- (1) All registers shown except the `rden` register have asynchronous clear ports.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

Each IOE contains its own control signal selection for the following control signals: oe, ce_in, ce_out, aclr/preset, sclr/preset, clk_in, and clk_out. Figure 2-63 illustrates the control signal selection.

Figure 2-63. Control Signal Selection per IOE



In normal bidirectional operation, the input register can be used for input data requiring fast setup times. The input register can have its own clock input and clock enable separate from the OE and output registers. The output register can be used for data requiring fast clock-to-output performance. The OE register can be used for fast clock-to-output enable timing. The OE and output register share the same clock source and the same clock enable source from local interconnect in the associated LAB, dedicated I/O clocks, and the column and row interconnects. Figure 2-64 shows the IOE in bidirectional configuration.

Figure 2–65. Stratix IOE in DDR Input I/O Configuration *Note (1)***Notes to Figure 2–65:**

- (1) All input signals to the IOE can be inverted at the IOE.
- (2) This signal connection is only allowed on dedicated DQ function pins.
- (3) This signal is for dedicated DQS function pins only.

However, there is additional resistance present between the device ball and the input of the receiver buffer, as shown in Figure 2–72. This resistance is because of package trace resistance (which can be calculated as the resistance from the package ball to the pad) and the parasitic layout metal routing resistance (which is shown between the pad and the intersection of the on-chip termination and input buffer).

Figure 2–72. Differential Resistance of LVDS Differential Pin Pair (R_D)

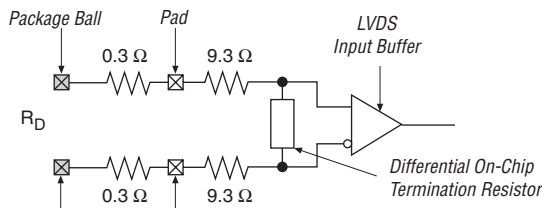


Table 2–35 defines the specification for internal termination resistance for commercial devices.

Table 2–35. Differential On-Chip Termination

Symbol	Description	Conditions	Resistance			Unit
			Min	Typ	Max	
R_D (2)	Internal differential termination for LVDS	Commercial (1), (3)	110	135	165	W
		Industrial (2), (3)	100	135	170	W

Notes to Table 2–35:

- (1) Data measured over minimum conditions ($T_j = 0\text{ C}$, $V_{CCIO} + 5\%$) and maximum conditions ($T_j = 85\text{ C}$, $V_{CCIO} = -5\%$).
- (2) Data measured over minimum conditions ($T_j = -40\text{ C}$, $V_{CCIO} + 5\%$) and maximum conditions ($T_j = 100\text{ C}$, $V_{CCIO} = -5\%$).
- (3) LVDS data rate is supported for 840 Mbps using internal differential termination.

MultiVolt I/O Interface

The Stratix architecture supports the MultiVolt I/O interface feature, which allows Stratix devices in all packages to interface with systems of different supply voltages.

The Stratix V_{CCINT} pins must always be connected to a 1.5-V power supply. With a 1.5-V V_{CCINT} level, input pins are 1.5-V, 1.8-V, 2.5-V, and 3.3-V tolerant. The V_{CCIO} pins can be connected to either a 1.5-V, 1.8-V, 2.5-V, or 3.3-V power supply, depending on the output requirements.

synthesis, allowing real-time variation of the PLL frequency and delay. The rest of the device is functional while reconfiguring the PLL. See the *Stratix Architecture* chapter of the *Stratix Device Handbook, Volume 1* for more information on Stratix PLLs.

Remote Update Configuration Modes

Stratix devices also support remote configuration using an Altera enhanced configuration device (e.g., EPC16, EPC8, and EPC4 devices) with page mode selection. Factory configuration data is stored in the default page of the configuration device. This is the default configuration that contains the design required to control remote updates and handle or recover from errors. You write the factory configuration once into the flash memory or configuration device. Remote update data can update any of the remaining pages of the configuration device. If there is an error or corruption in a remote update configuration, the configuration device reverts back to the factory configuration information.

There are two remote configuration modes: remote and local configuration. You can use the remote update configuration mode for all three configuration modes: serial, parallel synchronous, and parallel asynchronous. Configuration devices (for example, EPC16 devices) only support serial and parallel synchronous modes. Asynchronous parallel mode allows remote updates when an intelligent host is used to configure the Stratix device. This host must support page mode settings similar to an EPC16 device.

Remote Update Mode

When the Stratix device is first powered up in remote update programming mode, it loads the configuration located at page address "000." The factory configuration should always be located at page address "000," and should never be remotely updated. The factory configuration contains the required logic to perform the following operations:

- Determine the page address/load location for the next application's configuration data
- Recover from a previous configuration error
- Receive new configuration data and write it into the configuration device

The factory configuration is the default and takes control if an error occurs while loading the application configuration.

Table 4–2. Stratix Device Recommended Operating Conditions (Part 2 of 2)

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_{CCIO}	Supply voltage for output buffers, 3.3-V operation	(4), (5)	3.00 (3.135)	3.60 (3.465)	V
	Supply voltage for output buffers, 2.5-V operation	(4)	2.375	2.625	V
	Supply voltage for output buffers, 1.8-V operation	(4)	1.71	1.89	V
	Supply voltage for output buffers, 1.5-V operation	(4)	1.4	1.6	V
V_I	Input voltage	(3), (6)	–0.5	4.0	V
V_O	Output voltage		0	V_{CCIO}	V
T_J	Operating junction temperature	For commercial use	0	85	°C
		For industrial use	–40	100	°C

Table 4–3. Stratix Device DC Operating Conditions Note (7) (Part 1 of 2)

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
I_I	Input pin leakage current	$V_I = V_{CCIOmax}$ to 0 V (8)	–10		10	μA
I_{OZ}	Tri-stated I/O pin leakage current	$V_O = V_{CCIOmax}$ to 0 V (8)	–10		10	μA
I_{CC0}	V_{CC} supply current (standby) (All memory blocks in power-down mode)	V_I = ground, no load, no toggling inputs				mA
		EP1S10. V_I = ground, no load, no toggling inputs		37		mA
		EP1S20. V_I = ground, no load, no toggling inputs		65		mA
		EP1S25. V_I = ground, no load, no toggling inputs		90		mA
		EP1S30. V_I = ground, no load, no toggling inputs		114		mA
		EP1S40. V_I = ground, no load, no toggling inputs		145		mA
		EP1S60. V_I = ground, no load, no toggling inputs		200		mA
		EP1S80. V_I = ground, no load, no toggling inputs		277		mA

Table 4–3. Stratix Device DC Operating Conditions *Note (7) (Part 2 of 2)*

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
R _{CONF}	Value of I/O pin pull-up resistor before and during configuration	V _{CCIO} = 3.0 V (9)	20		50	kΩ
		V _{CCIO} = 2.375 V (9)	30		80	kΩ
		V _{CCIO} = 1.71 V (9)	60		150	kΩ

Table 4–4. LVTTTL Specifications

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V _{CCIO}	Output supply voltage		3.0	3.6	V
V _{IH}	High-level input voltage		1.7	4.1	V
V _{IL}	Low-level input voltage		–0.5	0.7	V
V _{OH}	High-level output voltage	I _{OH} = –4 to –24 mA (10)	2.4		V
V _{OL}	Low-level output voltage	I _{OL} = 4 to 24 mA (10)		0.45	V

Table 4–5. LVCMOS Specifications

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V _{CCIO}	Output supply voltage		3.0	3.6	V
V _{IH}	High-level input voltage		1.7	4.1	V
V _{IL}	Low-level input voltage		–0.5	0.7	V
V _{OH}	High-level output voltage	V _{CCIO} = 3.0, I _{OH} = –0.1 mA	V _{CCIO} – 0.2		V
V _{OL}	Low-level output voltage	V _{CCIO} = 3.0, I _{OL} = 0.1 mA		0.2	V

Table 4–6. 2.5-V I/O Specifications

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V _{CCIO}	Output supply voltage		2.375	2.625	V
V _{IH}	High-level input voltage		1.7	4.1	V
V _{IL}	Low-level input voltage		–0.5	0.7	V
V _{OH}	High-level output voltage	I _{OH} = –1 mA (10)	2.0		V
V _{OL}	Low-level output voltage	I _{OL} = 1 mA (10)		0.4	V

Performance

Table 4–36 shows Stratix performance for some common designs. All performance values were obtained with Quartus II software compilation of LPM, or MegaCore® functions for the FIR and FFT designs.

Table 4–36. Stratix Performance (Part 1 of 2) Notes (1), (2)

Applications		Resources Used			Performance				
		LEs	TriMatrix Memory Blocks	DSP Blocks	-5 Speed Grade	-6 Speed Grade	-7 Speed Grade	-8 Speed Grade	Units
LE	16-to-1 multiplexer (1)	22	0	0	407.83	324.56	288.68	228.67	MHz
	32-to-1 multiplexer (3)	46	0	0	318.26	255.29	242.89	185.18	MHz
	16-bit counter	16	0	0	422.11	422.11	390.01	348.67	MHz
	64-bit counter	64	0	0	321.85	290.52	261.23	220.5	MHz
TriMatrix memory M512 block	Simple dual-port RAM 32 × 18 bit	0	1	0	317.76	277.62	241.48	205.21	MHz
	FIFO 32 × 18 bit	30	1	0	319.18	278.86	242.54	206.14	MHz
TriMatrix memory M4K block	Simple dual-port RAM 128 × 36 bit	0	1	0	290.86	255.55	222.27	188.89	MHz
	True dual-port RAM 128 × 18 bit	0	1	0	290.86	255.55	222.27	188.89	MHz
	FIFO 128 × 36 bit	34	1	0	290.86	255.55	222.27	188.89	MHz
TriMatrix memory M-RAM block	Single port RAM 4K × 144 bit	1	1	0	255.95	223.06	194.06	164.93	MHz
	Simple dual-port RAM 4K × 144 bit	0	1	0	255.95	233.06	194.06	164.93	MHz
	True dual-port RAM 4K × 144 bit	0	1	0	255.95	233.06	194.06	164.93	MHz
	Single port RAM 8K × 72 bit	0	1	0	278.94	243.19	211.59	179.82	MHz
	Simple dual-port RAM 8K × 72 bit	0	1	0	255.95	223.06	194.06	164.93	MHz
	True dual-port RAM 8K × 72 bit	0	1	0	255.95	223.06	194.06	164.93	MHz
	Single port RAM 16K × 36 bit	0	1	0	280.66	254.32	221.28	188.00	MHz
	Simple dual-port RAM 16K × 36 bit	0	1	0	269.83	237.69	206.82	175.74	MHz

Table 4–75. EP1S30 External I/O Timing on Column Pins Using Global Clock Networks (Part 2 of 2)

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{XZ}	2.754	5.406	2.754	5.848	2.754	6.412	2.754	7.159	ns
t_{ZX}	2.754	5.406	2.754	5.848	2.754	6.412	2.754	7.159	ns
$t_{INSUPLL}$	1.265		1.236		1.403		1.756		ns
t_{INHPLL}	0.000		0.000		0.000		0.000		ns
$t_{OUTCOPLL}$	1.068	2.302	1.068	2.483	1.068	2.510	1.068	2.423	ns
t_{XZPLL}	1.008	2.176	1.008	2.351	1.008	2.386	1.008	2.308	ns
t_{ZXPLL}	1.008	2.176	1.008	2.351	1.008	2.386	1.008	2.308	ns

Table 4–76. EP1S30 External I/O Timing on Row Pins Using Fast Regional Clock Networks

Parameters	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{INSU}	2.616		2.808		3.223		3.797		ns
t_{INH}	0.000		0.000		0.000		0.000		ns
t_{OUTCO}	2.542	5.114	2.542	5.502	2.542	5.965	2.542	6.581	ns
t_{XZ}	2.569	5.168	2.569	5.558	2.569	6.033	2.569	6.663	ns
t_{ZX}	2.569	5.168	2.569	5.558	2.569	6.033	2.569	6.663	ns

Table 4–108. Stratix I/O Standard Output Delay Adders for Slow Slew Rate on Row Pins

I/O Standard		-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
LVCMOS	2 mA		1,571		1,650		1,650		1,650	ps
	4 mA		594		624		624		624	ps
	8 mA		208		218		218		218	ps
	12 mA		0		0		0		0	ps
3.3-V LVTTTL	4 mA		1,571		1,650		1,650		1,650	ps
	8 mA		1,393		1,463		1,463		1,463	ps
	12 mA		596		626		626		626	ps
	16 mA		562		590		590		590	ps
2.5-V LVTTTL	2 mA		2,562		2,690		2,690		2,690	ps
	8 mA		1,343		1,410		1,410		1,410	ps
	12 mA		864		907		907		907	ps
	16 mA		945		992		992		992	ps
1.8-V LVTTTL	2 mA		6,306		6,621		6,621		6,621	ps
	8 mA		3,369		3,538		3,538		3,538	ps
	12 mA		2,932		3,079		3,079		3,079	ps
1.5-V LVTTTL	2 mA		9,759		10,247		10,247		10,247	ps
	4 mA		6,830		7,172		7,172		7,172	ps
	8 mA		5,699		5,984		5,984		5,984	ps
GTL+			–333		–350		–350		–350	ps
CTT			591		621		621		621	ps
SSTL-3 Class I			267		280		280		280	ps
SSTL-3 Class II			–346		–363		–363		–363	ps
SSTL-2 Class I			481		505		505		505	ps
SSTL-2 Class II			–58		–61		–61		–61	ps
SSTL-18 Class I			2,207		2,317		2,317		2,317	ps
1.5-V HSTL Class I			1,966		2,064		2,064'		2,064	ps
1.8-V HSTL Class I			1,208		1,268		1,460		1,720	ps

Table 4–110. Stratix IOE Programmable Delays on Row Pins *Note (1)*

Parameter	Setting	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
Decrease input delay to internal cells	Off		3,970		4,367		5,022		5,908	ps
	Small		3,390		3,729		4,288		5,045	ps
	Medium		2,810		3,091		3,554		4,181	ps
	Large		173		181		208		245	ps
	On		173		181		208		245	ps
Decrease input delay to input register	Off		3,900		4,290		4,933		5,804	ps
	On		0		0		0		0	ps
Decrease input delay to output register	Off		1,240		1,364		1,568		1,845	ps
	On		0		0		0		0	ps
Increase delay to output pin	Off		0		0		0		0	ps
	On		397		417		417		417	ps
Increase delay to output enable pin	Off		0		0		0		0	ps
	On		348		383		441		518	ps
Increase output clock enable delay	Off		0		0		0		0	ps
	Small		180		198		227		267	ps
	Large		260		286		328		386	ps
	On		260		286		328		386	ps
Increase input clock enable delay	Off		0		0		0		0	ps
	Small		180		198		227		267	ps
	Large		260		286		328		386	ps
	On		260		286		328		386	ps
Increase output enable clock enable delay	Off		0		0		0		0	ps
	Small		540		594		683		804	ps
	Large		1,016		1,118		1,285		1,512	ps
	On		1,016		1,118		1,285		1,512	ps
Increase t_{ZX} delay to output pin	Off		0		0		0		0	ps
	On		1,993		2,092		2,092		2,092	ps

Note to Table 4–109 and Table 4–110:

- (1) The delay chain delays vary for different device densities. These timing values only apply to EP1S30 and EP1S40 devices. Reference the timing information reported by the Quartus II software for other devices.

Table 4–130. Enhanced PLL Specifications for -8 Speed Grade (Part 3 of 3)

Symbol	Parameter	Min	Typ	Max	Unit
t_{LSKEW}	Clock skew between two external clock outputs driven by the same counter		± 50		ps
t_{SKEW}	Clock skew between two external clock outputs driven by the different counters with the same settings		± 75		ps
f_{SS}	Spread spectrum modulation frequency	30		150	kHz
% spread	Percentage spread for spread spectrum frequency (10)	0.5		0.6	%
t_{ARESET}	Minimum pulse width on areset signal	10			ns

Notes to Tables 4–127 through 4–130:

- (1) The minimum input clock frequency to the PFD (f_{IN}/N) must be at least 3 MHz for Stratix device enhanced PLLs.
- (2) Use this equation ($f_{OUT} = f_{IN} * ml(n \times \text{post-scale counter})$) in conjunction with the specified f_{INPFD} and f_{VCO} ranges to determine the allowed PLL settings.
- (3) See “Maximum Input & Output Clock Rates” on page 4–76.
- (4) t_{FCOMP} can also equal 50% of the input clock period multiplied by the pre-scale divider n (whichever is less).
- (5) This parameter is timing analyzed by the Quartus II software because the `scanc1k` and `scandata` ports can be driven by the logic array.
- (6) Actual jitter performance may vary based on the system configuration.
- (7) Total required time to reconfigure and lock is equal to $t_{DLOCK} + t_{CONFIG}$. If only post-scale counters and delays are changed, then t_{DLOCK} is equal to 0.
- (8) When using the spread-spectrum feature, the minimum VCO frequency is 500 MHz. The maximum VCO frequency is determined by the speed grade selected.
- (9) Lock time is a function of PLL configuration and may be significantly faster depending on bandwidth settings or feedback counter change increment.
- (10) Exact, user-controllable value depends on the PLL settings.
- (11) The LOCK circuit on Stratix PLLs does not work for industrial devices below -20C unless the PFD frequency > 200 MHz. See the *Stratix FPGA Errata Sheet* for more information on the PLL.

Table 4–132. Fast PLL Specifications for -7 Speed Grades (Part 2 of 2)

Symbol	Parameter	Min	Max	Unit
t_{JITTER}	Period jitter for DIFFIO clock out (6)		(5)	ps
t_{LOCK}	Time required for PLL to acquire lock	10	100	μs
m	Multiplication factors for m counter (7)	1	32	Integer
l_0, l_1, g_0	Multiplication factors for l_0, l_1 , and g_0 counter (7), (8)	1	32	Integer
t_{ARESET}	Minimum pulse width on areset signal	10		ns

Table 4–133. Fast PLL Specifications for -8 Speed Grades (Part 1 of 2)

Symbol	Parameter	Min	Max	Unit
f_{IN}	CLKIN frequency (1), (3)	10	460	MHz
f_{INPFD}	Input frequency to PFD	10	500	MHz
f_{OUT}	Output frequency for internal global or regional clock (4)	9.375	420	MHz
$f_{\text{OUT_DIFFIO}}$	Output frequency for external clock driven out on a differential I/O data channel	(5)	(5)	MHz
f_{VCO}	VCO operating frequency	300	700	MHz
t_{INDUTY}	CLKIN duty cycle	40	60	%
t_{INJITTER}	Period jitter for CLKIN pin		±200	ps
t_{DUTY}	Duty cycle for DIFFIO 1× CLKOUT pin (6)	45	55	%
t_{JITTER}	Period jitter for DIFFIO clock out (6)		(5)	ps
t_{LOCK}	Time required for PLL to acquire lock	10	100	μs
m	Multiplication factors for m counter (7)	1	32	Integer
l_0, l_1, g_0	Multiplication factors for l_0, l_1 , and g_0 counter (7), (8)	1	32	Integer

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